

**Search Notes**

Application/Control No.

10/655,151

Examiner

Ahmed M. Farah

Applicant(s)/Patent under  
Reexamination

YEE ET AL.

Art Unit

3739

**SEARCHED**

Class	Subclass	Date	Examiner
606	4-6,8-11	8/22/2005	AF
351	211-216	8/22/2005	AF
128	898	8/22/2005	AF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search Histor Printout		8/22/2005	

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Search; and EAST search: Classification (IS&R); and Text (BRS)	8/22/2005	AF
Searched Data Basis: USPAT; USPGPUB; EPO; JPO; DERWENT; and IBM_TDB.	8/22/2005	AF
See the attached "Search History."	8/22/2005	AF